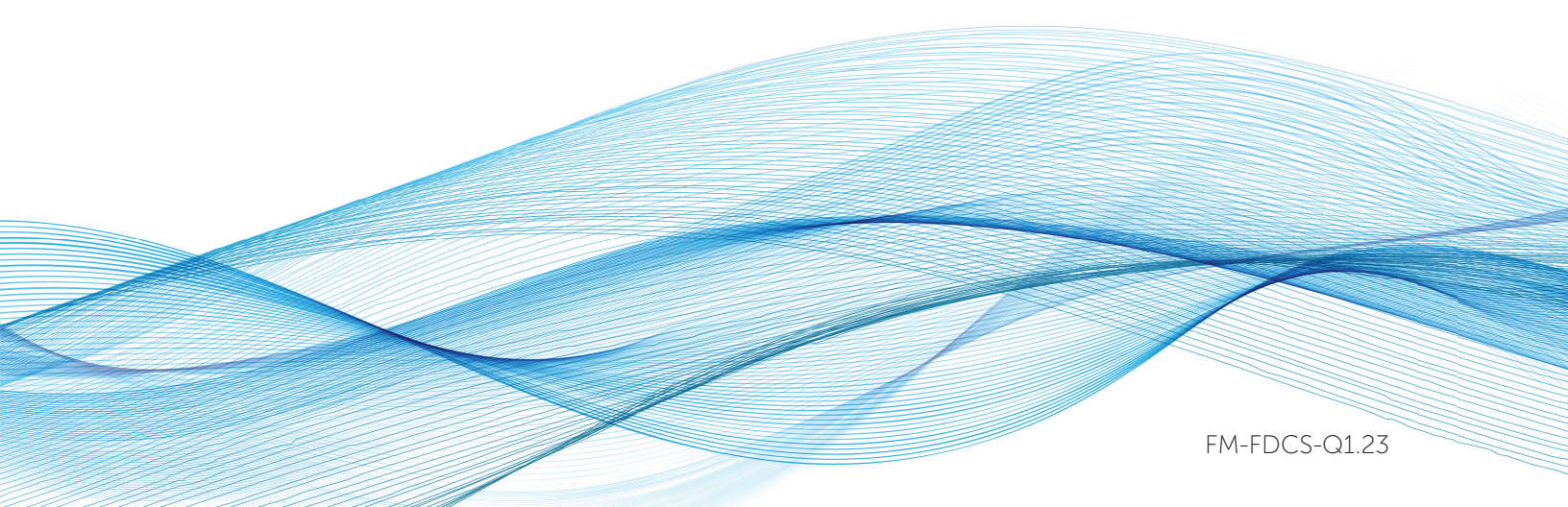
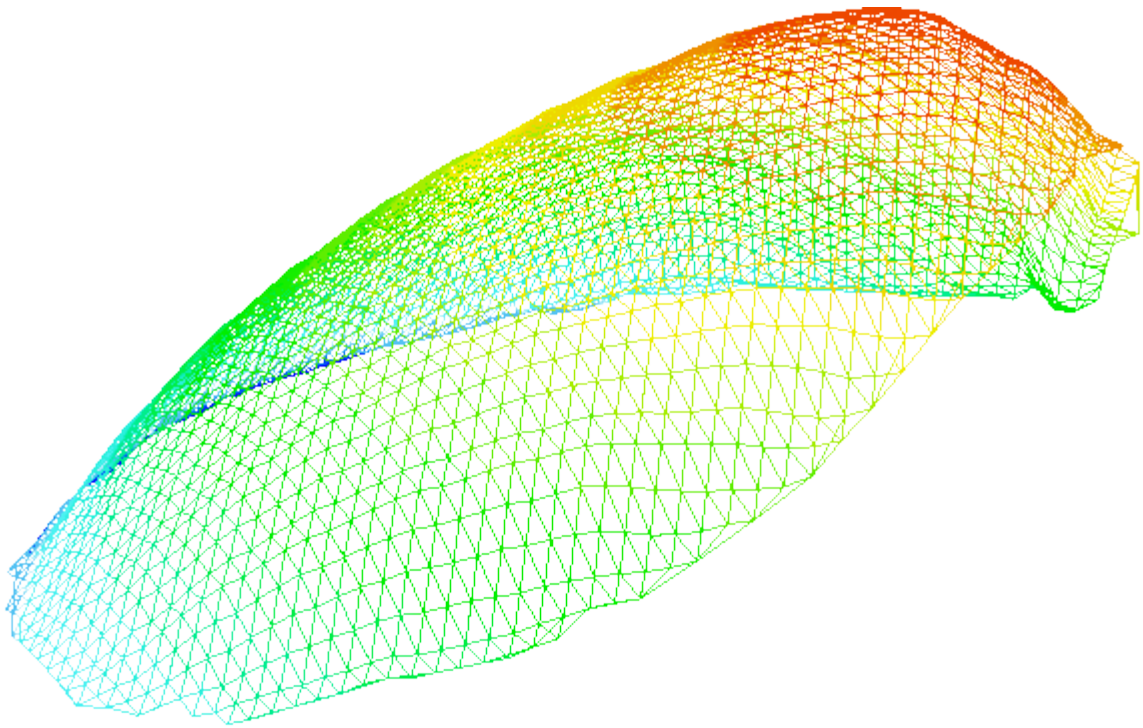




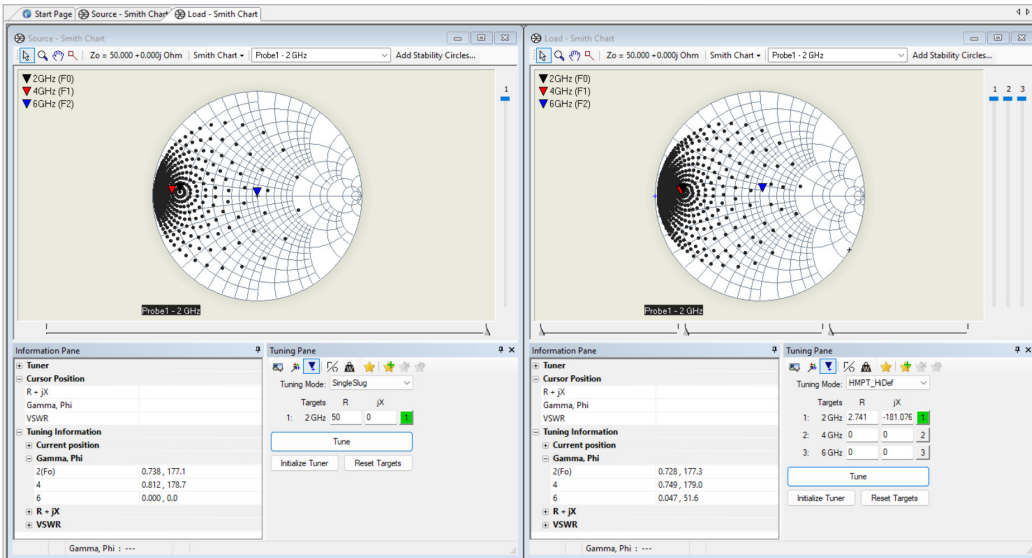
FDCS

Focus Device Characterization Suite



Introduction | FDCS Focus Device Characterization Suite

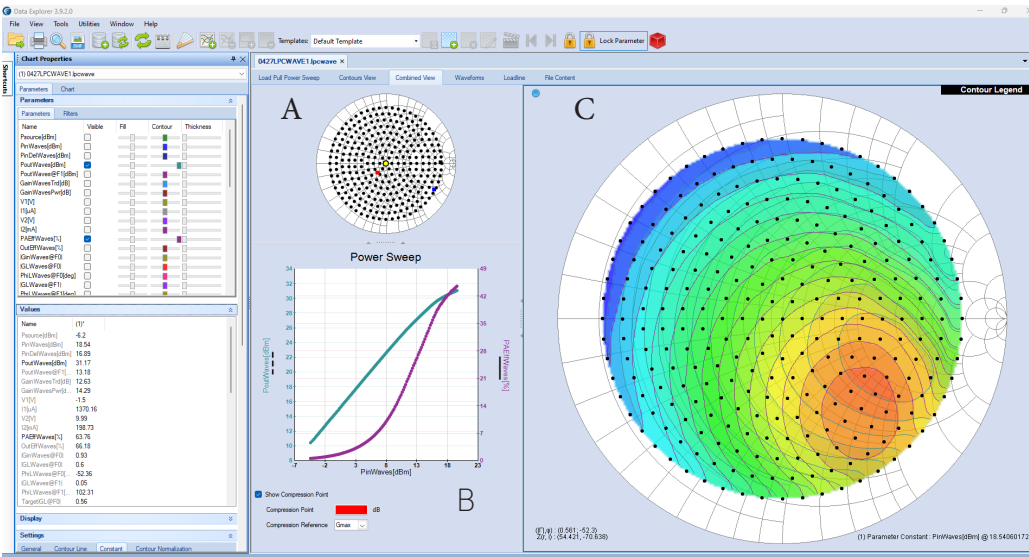
FDCS includes several software products aimed at characterizing transistor devices. These comprise of Load pull, Noise parameters extraction, data plotting and API functionalities. Advanced utilities are available for tuner control/calibration, driver-based instrument communication, and reference plane de-embedding. FDCS incorporates advanced software routines for Scalar Load Pull, Time-domain based Vector Load Pull and Hybrid active injection Load Pull allowing the combination of active injection and passive tuning.



Load Pull User Interface

Data Explorer

Data Explorer is included in FDCS for graphical display of any measurement data produced from Load Pull, Noise or I/V measurements.



Plot A: Measured Impedance Points
Plot B: Power Sweep Curve
Plot C: Contour for Pout and PAE

FDCS Licences and Options

